How to Design Synchronous Buck Converter Using GaN FET Compatible Analog Controllers with Integrated Gate Drivers

Introduction

Conventional MOSFET analog controller IC's are not fully compatible with eGaN® FETs because of the specific driving needs. For example, there is no over-voltage management for the bootstrap supply in the event where the lower FET reverse conducts [1], and high negative voltage spikes on the switch node during dead time can lead to unpredictable timing behavior. As a result, digital controllers such as DSP's have been used for eGaN FET based designs but require additional support IC's such as a current sense amplifier, housekeeping power supply, and eGaN FET compatible gate driver [2]. This approach adds to the overall bill-of-material (BoM) and increases design complexity [3].

Recently, the eco-system for GaN FETs, such as GaN compatible analog controllers with integrated gate drivers, has evolved which drastically simplify the design when using GaN FETs. For example, the LTC7890 which is used in this design, is a GaN compatible analog controller that has integrated GaN drivers and no additional support IC's are required. This application note will cover the layout and thermal design challenges. Finally, the performances are demonstrated by two design examples: a 48 V-12 V 600 W 2-phase buck converter and a 24 V to 5 V/3.3 V, 2 MHz dual output buck converter.

Example 1: A 600 W 2-phase buck converter

A. FET selection: asymmetric vs symmetric half bridge

For this 48 V to 12 V 600 W application, two GaN FETs, the 100 V rated, 6 m Ω EPC2204 and the 100 V rated, 3.2 m Ω EPC2218 are considered. We compared the projected FET losses and temperature in three half bridge configurations as shown in Table 1. Since the bottom FET conducts 75% of the time, at high output current, the conduction loss in bottom FET become a dominant loss factor. The symmetrical EPC2204 has the highest losses and temperatures because of the higher on-resistance. In the asymmetrical EPC2204 and EPC2218 case, the efficiency is very similar to the symmetrical EPC2218 case at high (23 A) load and predicts higher efficiency at light load, however, the upper FET EPC2204 experiences overheating due to the smaller die size and higher thermal resistance with less thermal vias beneath the solder pads. Overall, the symmetrical EPC2218 shows the best performance in both losses and thermal performance metrics.

B. Optimizing layout

To take advantage of the fast switching of chip scale package (CSP) eGaN FETs, the gate and power loop parasitic inductances need to be minimized. As can be seen in Figure 1, the power loop (in red) is formed by the FETs and input decoupling capacitors, and the power loop inductance affects switching behavior. To minimize switching losses

Symmetrical EPC2204	3.2 W 5 W	126°C 141°C
Symmetrical EPC2218	3.2 W 2.4 W	94°C 89°C
Asymmetrical EPC2204 (high side) + EPC2218 (low side)	3.4 W 2.4 W	112℃ 91℃

HB configuration

Table 1. Comparison of different half bridge configurations $(V_{IN} = 48 V, V_{OUT} = 12 V, I_{OUT} = 23 A).$



Figure 1. Layout of the FET and the LTC7890 controller IC showing critical commutation loops. The gate loop and power loop are orthogonal.

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 T_{hs}/T_{ls}

FEA simulation



 P_{hs}/P_{ls}

Loss model

and reduce ringing, power loop inductances should be minimized. One approach is to use the internal vertical loop layout discussed in [4], in which the second layer of the printed circuit board (PCB) is a solid ground return plane. Similarly, the high side (in blue) and low side (in green) gate loop inductances should also be minimized to reduce ringing on the gate thus preventing gate over-voltage. **In a buck converter, the high side FET is hard switched while the low side FET is soft switched, the high side gate loop is intentionally prioritized and made smaller than the low side gate loop given physical constraints of the IC and layout.** Note the direction of the power and gate loops are spatially orthogonal to each other, which helps reducing common source inductances.

Layout will also affect thermal management. Even though eGaN FETs are very efficient, the small area of the non-packaged eGaN FETs requires attention for thermal management. In this example, no heatsink is used therefore it is important to maximize the number of vias under the eGaN FETs which greatly improves thermal heat-spreading from the FET into the copper layers of the PCB. A thermal simulation in Figure 2 shows the vias conducting heat from FET to the bottom layer of the PCB. Note the number of PCB layers, copper weight, the structure of the vias and the stack up of the PCB also affect thermal performance [5].

C. Experimental Results:

EPC9158 is a 48 V to 12 V, 600 W buck converter, targeted for data center and automotive 48 V applications. EPC2218 is used and the switching frequency is 500 kHz and the inductor is 2 μ H (SER2011-202). With 400 LFM airflow, the measured thermal steady state efficiency is shown in Figure 3, for a range of input voltages from 36 V through 54 V and output current up to 50 A. For 48 V input, the peak efficiency is 96.5% that occurs when the output current is around 30 A (60% load). At full power, the maximum device temperature reached 91°C, as illustrated in the thermal image in Figure 4.



Figure 2. Cross-sectional view of a thermal simulation result for the CSP GaN FETs mounted on a 6-layer Printed Circuit Board showing the vias as heat flow paths.





Figure 3. Measured EPC9158 efficiency and power loss results for 28-54 V input range and 12 V output.



Figure 4. (Left) EPC9158 board (right) thermal results tested at V_{IN} = 48 V, V_{OUT} = 12 V, f_s = 0.5 MHz, I_{OUT} = 50 A, 400 LFM forced air cooling.

Example 2: A 2 MHz dual-output buck converter

EPC9160, as shown in Figure 5 (left), is a 2 MHz, 24 V to dual output voltage (5 V and 3.3 V) buck converter, designed in a similar manner as EPC9158. High switching frequency was chosen based on EMI requirements in automotive applications, and it further demonstrates the fast switching speed of GaN FETs together with the smaller size of the inductor and capacitors. The entire EPC9160 power stage fits within an area of just 506 mm² (W = 23 mm, L = 22 mm).

Figure 5 shows the efficiency and power loss performance results for various input voltages, ranging from 12 V through 24 V. A peak efficiency of 96% is achieved with 12 V input and 5 V output. Worst case thermal result with 24 V input and no forced air cooling is shown in Figure 6 (right), where the device temperature reached 77°. The vias underneath the FETs and the 6-layer PCB with 2oz copper thickness help in reducing the temperature of the FETs by utilizing heat-spreading of the PCB copper layers.



Figure 5. Measured EPC9160 efficiency and power loss results for 12-24 V input range and 5 V output.



Figure 6. (left) EPC9160 board (right) thermal results tested at $V_{IN} = 24 V$, $V_{OUT} = 5 V$, fs = 2 MHz, $I_{OUT} = 10 A$, no forced air cooling.

Conclusion

This application note discusses the simplified design of GaN FETs with analog controllers. GaN compatible eco-system such as controllers with integrated gate divers greatly simplifies the design and result in reduced number of BoM components. Two example designs; EPC9158 which is a 48 V to 12 V, 600 W buck converter and EPC9160 which is a 2 MHz 12-24 V to 5 V/3.3 V buck converter, are used to demonstrate the high performance of GaN FETs, including high efficiency and good thermal performance. Good layout practice is important in achieving the best performance that GaN FETs have to offer.

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